

### WIREBONDS STATUS

dE				E-front				E-back				Last checked	
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	date	detector
1				1				1				10/2/07	dE, Ef, Eb
2				2				2					
3				3				3					
4				4				4					
5				5				5					
6				6				6					
7				7				7					
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12				12				12					
13				13				13					
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30				30				30					
31				31				31					
32				32				32					

**Legend:**  
X = bond missing    / = bond broken    ~ = bond damaged

T22 11

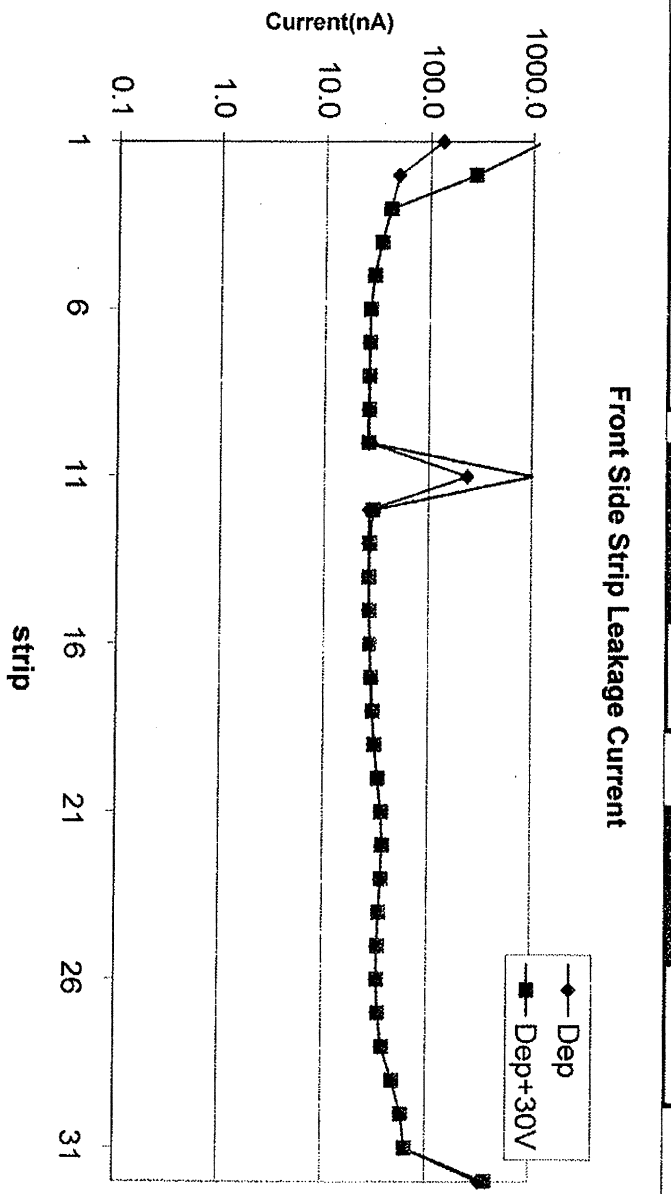
ΔE = 2297-10  
E = 2344-03

### Front Side Data

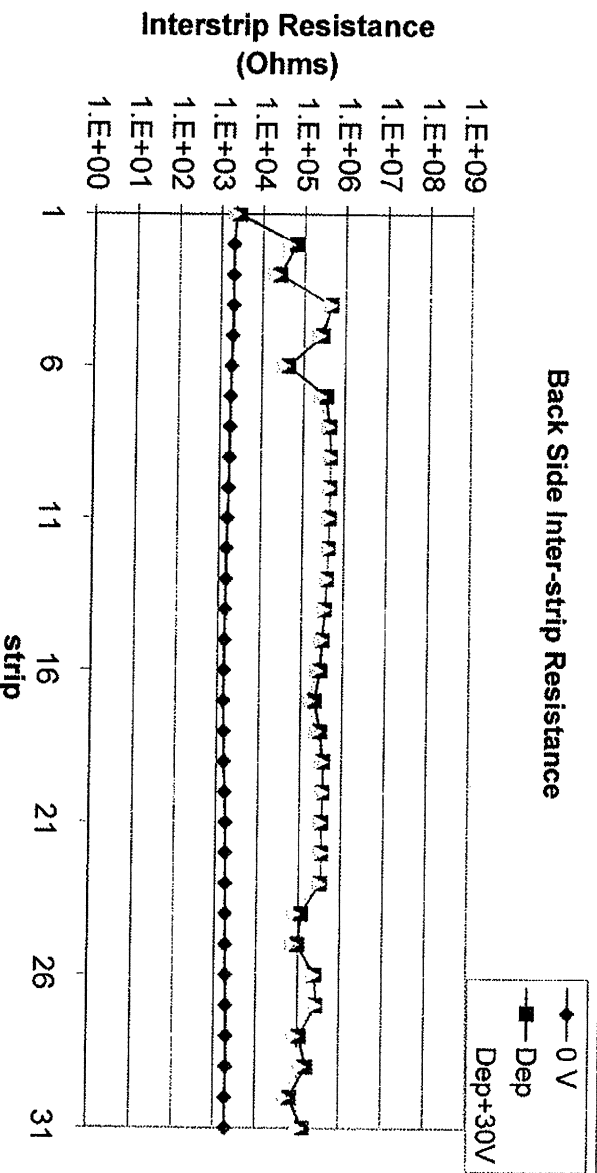
Wafer No.: **2344-3** Thickness: **1491** um Depletion: **350** Volts

### Back Side Data

Strip	Current(nA)	Dep	Dep+30V
1	132.33	1275.50	
2	49.34	280.00	
3	40.70	41.20	
4	34.00	34.07	
5	28.97	29.09	
6	26.88	26.86	
7	26.26	26.51	
8	26.02	26.28	
9	25.96	26.35	
10	25.79	26.07	
11	238.40	1021.90	
12	26.50	28.88	
13	26.70	27.02	
14	26.44	26.53	
15	26.65	27.01	
16	27.10	27.39	
17	27.81	28.12	
18	28.92	29.24	
19	30.44	30.76	
20	32.88	33.15	
21	35.54	35.80	
22	36.71	36.97	
23	35.67	35.92	
24	34.15	34.38	
25	33.28	33.52	
26	32.99	33.26	
27	33.90	34.17	
28	37.06	37.28	
29	46.92	47.52	
30	57.63	57.81	
31	62.58	63.03	
32	329.70	378.50	
Total	1584.02	3900.19	



Front Side Strip Leakage Current



Back Side Inter-strip Resistance

Strip	Back Resistance(Ω)	0V	Dep	Dep+30V
1	2.3E+03	2.7E+03	2.1E+03	
2	2.0E+03	6.3E+04	4.1E+04	
3	2.0E+03	2.6E+04	2.0E+04	
4	2.0E+03	4.5E+05	4.4E+05	
5	2.0E+03	2.9E+05	2.4E+05	
6	1.9E+03	4.3E+04	3.4E+04	
7	1.8E+03	3.6E+05	2.5E+05	
8	1.7E+03	4.4E+05	4.0E+05	
9	1.7E+03	4.6E+05	4.5E+05	
10	1.7E+03	4.5E+05	4.4E+05	
11	1.6E+03	4.4E+05	4.3E+05	
12	1.5E+03	4.2E+05	4.2E+05	
13	1.5E+03	4.0E+05	3.9E+05	
14	1.5E+03	3.6E+05	3.4E+05	
15	1.5E+03	3.3E+05	2.9E+05	
16	1.4E+03	2.9E+05	2.4E+05	
17	1.4E+03	2.7E+05	1.6E+05	
18	1.5E+03	3.0E+05	2.4E+05	
19	1.5E+03	3.6E+05	3.3E+05	
20	1.6E+03	3.5E+05	3.4E+05	
21	1.7E+03	3.4E+05	3.7E+05	
22	1.7E+03	3.3E+05	3.3E+03	
23	1.7E+03	3.2E+05	3.1E+05	
24	1.8E+03	1.3E+05	7.8E+04	
25	1.8E+03	9.7E+04	7.3E+04	
26	1.9E+03	2.6E+05	2.5E+05	
27	1.9E+03	2.7E+05	2.7E+05	
28	2.0E+03	1.1E+05	8.3E+04	
29	2.0E+03	1.6E+05	1.2E+05	
30	1.9E+03	6.7E+04	4.9E+04	
31	2.0E+03	1.4E+05	1.1E+05	

# Resolution Test

## HIRA BB7

Wafer No.: **2344-3**

Thickness: **1491**  $\mu\text{m}$

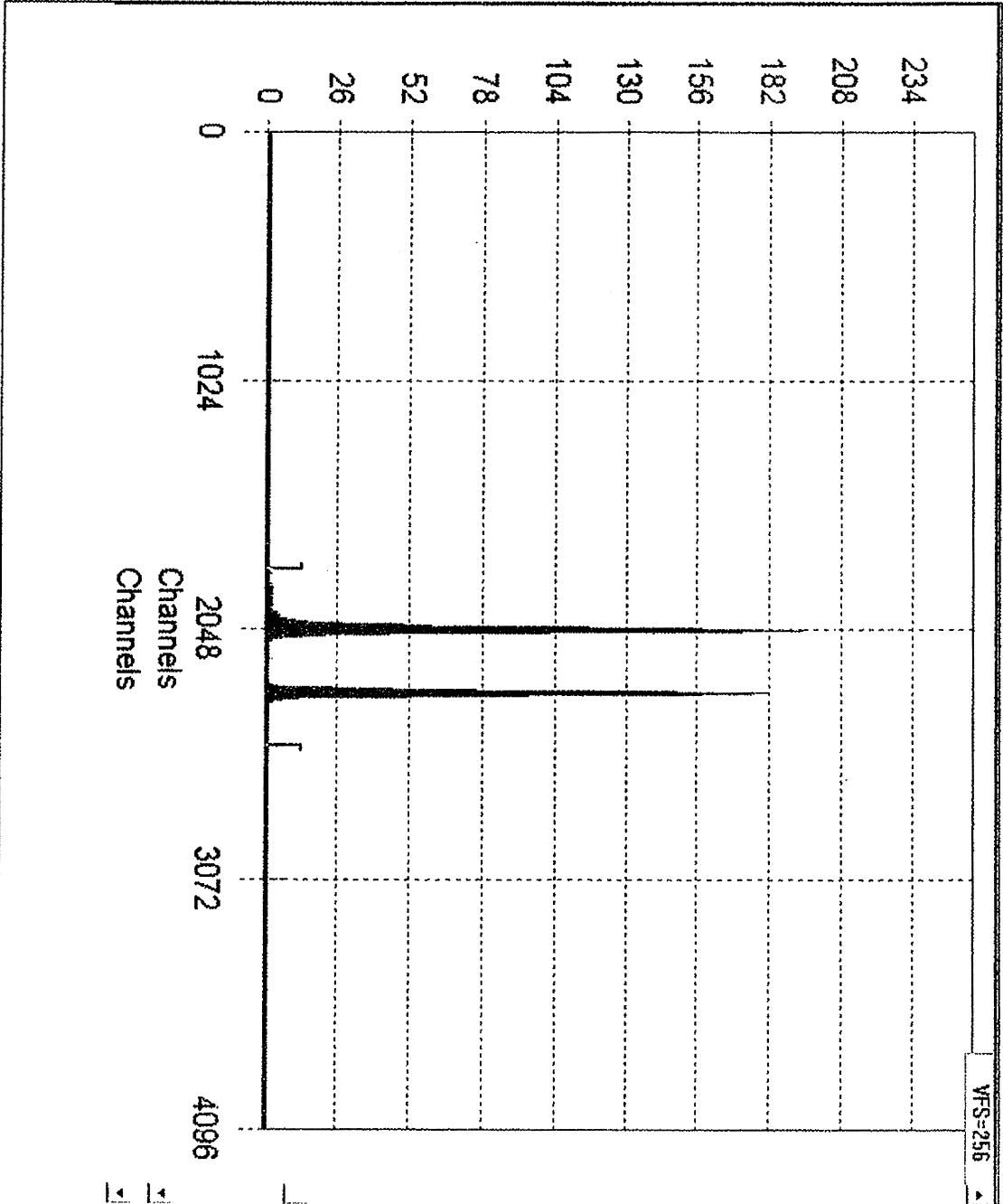
VFS-256

### JUNCTION

DET LINE: **59.1** KeV  
SYSTEM: **50** KeV  
CAL: **31.5** KeV

### CHM/C

DET LINE: **61.5** KeV  
SYSTEM: **49.9** KeV  
CALC: **36** KeV



BIAS VOLTS= **350** V Leakage **1400** nA

Source  
Am 241

Rise Time  
1

Flat Top  
0

# Si-detector Inspection Record

Date: 10/2/2007

Time: ~5:00pm

Tel n.: 11

Inspected detector(s): dE(2297-10) + E(2344-3)  
*dE removed*

1st inspector: Vlad HENZL

2nd inspector: Jana HENZLOVA

## WIREBONDS STATUS

dE				E-front				E-back			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1				1			
2				2				2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
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30				30				30			
31				31				31			
32				32				32			

**Legend:**

X = bond missing

/ = bond broken

~ = bond damaged

**Overall detector status:**

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)

E<sub>1</sub>, dE wirebonds look fine

E<sub>5</sub> wirebonds look fine.

**Noise tests of detector n.: 2344-03 in telescope n.: 11**

Date		9-12-07	10-10-07	10-31-07											
electronics		CLASSIC	CHIP	CHIP											
<b>E back</b>	<b>Chip 0 or shaper 0</b>	chn 0	5.0mV	35mV	~46mV										
		1	5	32	41mV										
		2	5	32	32										
		3	5	30	32										
		4	5	30	42										
		5	5	30	32										
		6	5	30	32										
		7	5	~45mV	~45mV										
		8	5	~45mV	~45mV										
		9	5	~30mV	~65mV										
		10	5	~35	32										
		11	5	35	32										
		12	5	32	32										
		13	5	32	32										
		14	6mV	32	32										
	15	7mV	32	32											
	<b>Chip 1 or shaper 1</b>	chn 0	7.8mV	35	~50mV										
		1	6.7	35	~40mV										
		2	6.4	~30	40										
		3	6.4	30	40										
		4	6.4	30	40										
		5	6.4	~40mV	40										
		6	6.4	~40mV	40										
		7	6.4	~30mV	40										
		8	6.4	~32	40										
		9	6.4	32	~70mV										
		10	6.4	32	32										
		11	6.4	32	32										
		12	6.4	30	32										
		13	6.4	30	32										
14		6.4	30	32											
15	8mV	32	32												
<b>E front</b>	<b>Chip 0 or shaper 2</b>	chn 0	28mV	~30mV	~42mV										
		1	8	30	32										
		2	8	30	32										
		3	8	30	32										
		4	17mV	30	32										
		5	12mV	30	32										
		6	8	30	32										
		7	9	30	32										
		8	9	30	32										
		9	9	30	32										
		10	13mV	30	32										
		11	8	30	32										
		12	9	30	32										
		13	9	30	32										
		14	15mV	30	32										
	15	9.5mV	30	~42mV											
	<b>Chip 1 or shaper 3</b>	chn 0	10	30	~40mV										
		1	9	30	40										
		2	15mV	30	32										
		3	6	30	32										
		4	9	30	32										
		5	18mV	30	32										
		6	9	30	32										
		7	6	30	32										
		8	7	30	32										
		9	11mV	30	32										
		10	15mV	~45mV	32										
		11	14mV	30	~40										
		12	13mV	30	32										
		13	9	~45mV	32										
14		8	30	~40											
15	8	30	~125mV												

identical setup  
before and after  
1st part of 05193

# Si-detector Inspection Record

**Date:** 10/1/2007      **Time:** 7:30 pm      **Tel n.:** 11

**Inspected detector(s):** dE(2297-10), EF

**What occasion :** dE put back in car

**1st inspector:** Vlad HENZL

**2nd inspector:** Davidla HENZLOVA

## WIREBONDS STATUS

dE				E-front				E-back			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1	~			1			
2				2	~			2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
9				9				9			
10				10				10			
11				11				11			
12				12				12			
13				13				13			
14				14				14			
15				15				15			
16				16				16			
17				17				17			
18				18				18			
19				19	~	~	~	19			
20				20	~	~	~	20			
21				21				21			
22				22				22			
23				23				23			
24				24				24			
25				25				25			
26				26				26			
27				27				27			
28				28				28			
29				29				29			
30			~	30				30			
31				31				31			
32				32				32			

**Legend:**

X = bond missing      / = bond broken      ~ = bond damaged

**Overall detector status:**

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)

Et wirebonds fairly good  
Et surface blown with dry N<sub>2</sub>